

Search Notes (continued)


Application/Control No.

10/004,900

Examiner

Tan Dean D. Nguyen

 Applicant(s)/Patent under
Reexamination

GRUBER ET AL.

Art Unit

3629

SEARCHED

	Class	Subclass	Date	Examiner
①	705	1	4/06	DN
2		14		
3		26		
②	463	42		
③	709	206	✓	✓

INTERFERENCE SEARCHED

	Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
I US	4/06	DN
a) Patent		
b) PG Pub		
II FOREIGN		
(1) EPO		
(2) JPO		
(3) Invent		
III NPL (dialogs)	✓	✓